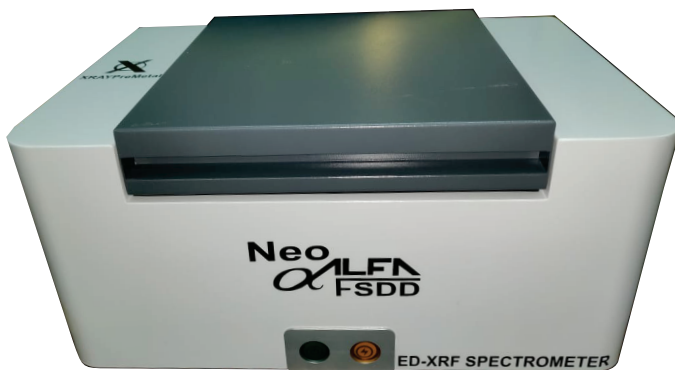


X-RAY

High Performance X-Ray Fluorescence Measuring Instrument for fast and non-destructive Material Analysis and Coating Thickness Measurement

Neo ALFA FSDD (MCR) / ALFA SDD / ALFA SI-Pin analysis, user-friendly interface Easy to analyze composition and karat results with one push of a button accurate chemistry and karat results within seconds Designed to be compact, taking up minimum desktop space.with Direct Shooting X-Ray, An attractive Design suitable for the showroom floor.Hallmarking Centre And Tunch Lab. Fast certificate results with PC software. Interior lighting and camera allows continuous sample viewing for Best customer security Easy access to the test results

www.neoXrf.com





Key Features

The two most distinctive features of the EXE Series are precision video imaging, and “bottom-up” measurement using a motorized Z-axis with laser-based auto-focus.

An available manual XY stage with 1.5X1.5” travel facilitates easy positioning of small and large parts.

Configuration

The standard configuration includes a single fixed collimator, solid-state PIN detector Silicon Drift Detector and long-life micro-focus x-ray tube/Silicon Drift Detector

Specifications

X-ray Excitation

50 W (50kV and 1mA) micro-focused Wanode tube

Detector

AmpTek Super Silicon Drift Detector (FSDD) with 100eV Resolution or Better

Focal Depth

Single fixed focal depth with laser and auto focus

Video Magnification

20x: Standard

Working Environment:

50° F (10°C) to 104°F (40°C) and up to 98% BIL, non-condensing

Weight

25kg

Optional Manual XY Sample Stage

Table Size 11x10”
Travel 1.5x1.5”

Element Range

Aluminum 13 to Uranium 92

Analysis layers and elements

5 layer (4 layers + base) and 10 elements in each layer
Composition analysis of up to 25 elements simultaneously

Filters/Collimators

4 primary filters / single collimator (optional dual)

Digital Pulse Processing

4096 CH digital multi-channel analyser with flexible shaping time. Automatic signal processing including dead time correction and escape peak correction.

Processor

Intel, CORE i5 3470 (3.2GHz), 8GB DDB3 Memory, Microsoft Windows 10 Prof, 64bit equivalent

Camera optics:

1/4” CMOS-1280x720 VGA resolution.

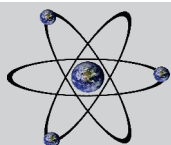
Power Supply:

150W, 100-240 volts, frequency range 47Hz to 63Hz

Dimensions (HxWxD)

Internal 'Comm 14”%, 325mm, 200mm (12”)
Exterra : 325mm (13”), 350mm (14”), 450mm (18”)

Coating Thickness Material Analysis Microhardness Material Testing



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